

Sub-electron readout noise in a Skipper CCD fabricated on high resistivity silicon

Guillermo Fernández Moroni · Juan Estrada ·
Gustavo Cancelo · Stephen E. Holland ·
Eduardo E. Paolini · H. Thomas Diehl

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Abstract The readout noise for Charge-Coupled Devices (CCDs) has been the main limitation when using these detectors for measuring small amplitude signals. A scientific CCD fabricated on a high-resistivity silicon substrate utilizing a floating gate amplifier with the capability of multiple sampling of the charge signal is described in this paper. The Skipper CCD architecture and its

G. Fernández Moroni (✉) · E. E. Paolini
Inst. de Inv. en Ing. Eléctrica (IIIE) “Alfredo C. Desages”, Dto. Ing. Eléctrica Comp.,
Universidad Nacional del Sur, Av. Alem 1253 - (B8000CPB) Bahía Blanca,
Buenos Aires, Argentina
e-mail: gfmoroni@fnal.gov

E. E. Paolini
e-mail: epaolini@uns.edu.ar

G. Fernández Moroni · J. Estrada · G. Cancelo · H. T. Diehl
Fermi National Accelerator Laboratory, Kirk Road and Pine Street, Batavia, IL 60510, USA

J. Estrada
e-mail: estrada@fnal.gov

G. Cancelo
e-mail: cancelo@fnal.gov

H. T. Diehl
e-mail: diehl@fnal.gov

G. Fernández Moroni
Comisión de Investigaciones Científicas y Técnicas (CONICET), Buenos Aires, Argentina

S. E. Holland
Lawrence Berkeley National Laboratory, 1 Cyclotron Road, Berkeley, CA 94729, USA
e-mail: seholland@lbl.gov

E. E. Paolini
Comisión de Investigaciones Científicas Prov. Buenos Aires (CIC), Buenos Aires, Argentina